

Method of analysis reference:

- *UNI EN 13925-1:2006 - Non-destructive testing - X-ray diffraction from polycrystalline and amorphous material - Part 1: General principles*
- *UNI EN 13925-2:2006 - Non-destructive testing - X-ray diffraction from polycrystalline and amorphous material - Part 2: Procedures*
- *UNI EN 13925-3:2005 - Non-destructive testing - X ray diffraction from polycrystalline and amorphous materials - Part 3: Instruments*

- X-Ray qualitative analysis

Diffractionmeter PANALYTICAL “XPRT-PRO”: main instrumental conditions:

Start Position [°2Th.]:	5.00	Goniometer Radius [mm]:	240.00
End Position [°2Th.]:	80.00	Dist. Focus-Diverg. Slit [mm]:	100.00
Step Size [°2Th.]:	0.0170	Incident Beam Monochromator:	No
Scan Step Time [s]:	15.2400	Spinning:	Yes
Scan Type:	Continuous	Divergence Slit Type:	Fixed
PSD Mode:	Scanning	Divergence Slit Size [°]:	0.4354
PSD Length [°2Th.]:	2.12	Specimen Length [mm]:	10.00
Offset [°2Th.]:	0.0000	Anode Material:	Cu
Divergence Slit Type:	Fixed	K-Alpha1 [Å]:	1.54060
Divergence Slit Size [°]:	0.4354	K-Alpha2 [Å]:	1.54443
Specimen Length [mm]:	10.00	K-Beta [Å]:	1.39225
Anode Material:	Cu	K-A2 / K-A1 Ratio:	0.50000
K-Alpha1 [Å]:	1.54060	Generator Settings:	40 mA, 40 kV
K-Alpha2 [Å]:	1.54443	Goniometer Radius [mm]:	240.00
K-Beta [Å]:	1.39225	Dist. Focus-Diverg. Slit [mm]:	100.00
K-A2 / K-A1 Ratio:	0.50000	Incident Beam Monochromator:	No
Generator Settings:	40 mA, 40 kV		